Test Org.*	Device	Function	Technology	Mfr.	Effective SEU LET* Threshold	Device Xsection (cm^2)	Bits Tested	Bit Xsection (cm^2)	Test Date	LUth	LU Xsection (cm^2)	Fac.	Remarks 30-Aug-99
		Voltage Reference											
	Note: Entries in **RED** indicate data added since the 1997 Compendium.												
GSFC	LM136AH	+2.5 V ref.	Bipolar	NSC					Jul-94			BNL	LaBel. D/C 9320.
GSFC	**LM136AH**	**+2.5 V ref.**	**Bipolar**	**NSC**	**3.38**				**1996**			**BNL**	**LaBel, et al, 97IEEE Wrkshp Rec., pg14. Short (<1 µs) errors.**
ARSP	**REF-02**	**+5 V ref.**	**Bipolar**	**ADI**	**3 to 6**	**1.0E-04 - 5.0E-04**			**1997**	**>60**		**UCB**	**Koga, et al, 97IEEE TNS, No. 6, pg. 2325.. D/C 9305. Weak LETth dependence on input voltage delta.**
GSFC	REF-02-373J	+5 V ref.	Bipolar	PMI					Jul-94	>100		BNL	LaBel. D/C Q8573944.
LMM	**RH1021**	**Precision Reference**	**Bipolar**	**LTC**	**18**	**1.4E-04**			**97-98**	**>84**		**BNL**	**Bogorad, et al, 99NSREC Poster Paper Preprint. X-section for all 20 µS transients > 0.2 V. Includes 0.1 µf capacitor, Vin = 15 V through 511 ohms.**
LMM	**RH1021**	**Precision Reference**	**Bipolar**	**LTC**	**18**	**5.6E-04**			**97-98**	**>84**		**BNL**	**Bogorad, et al, 99NSREC Poster Paper Preprint. X-section for all 5 µS transients > 0.2 V. No output capacitor, Vin = 15 V through 511 ohms.**
LMM	**RH1021**	**Precision Reference**	**Bipolar**	**LTC**	**18**	**1.1E-04**			**97-98**	**>84**		**BNL**	**Bogorad, et al, 99NSREC Poster Paper Preprint. X-section for all 5 µS transients > 1.0 V No output capacitor, Vin = 15 V through 511 ohms.**

Legend

Manufacturers: ADI - Analog Devices, Inc; NSC - National Semiconductor; PMI - Precision Monolithics, Inc

Test Organizations

ARSP - Aerospace Corp., El Segundo, CA

GSFC - Goddard Space Flight Center, Greenbelt, MD

LMM - Lockheed Martin Missiles and Space, Newtown, PA

Radiation Test Facilities

BNL - Tandem Van de Graaff, Brookhaven National Laboratories, Long Island, NY

UCB - 88-inch Cyclotron, University of California, Berkeley, CA